Welcome to E-XFL.COM

Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	547
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	69
Number of Gates	2000
Voltage - Supply	4.5V ~ 5.5V
Mounting Type	Through Hole
Operating Temperature	-55°C ~ 125°C (TC)
Package / Case	84-BCPGA
Supplier Device Package	84-CPGA (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a1020b-1pg84m

DESC SMD/Actel Part Number Cross Reference

Actel Part Number (Gold Leads)	DSCC SMD (Gold Leads)	DSCC SMD (Solder Dipped)
A1010B-PG84B	5962-9096403MXC	5962-9096403MXA
A1010B-1PG84B	5962-9096404MXC	5962-9096404MXA
A1020B-PG84B	5962-9096503MUC	5962-9096503MUA
A1020B-1PG84B	5962-9096504MUC	5962-9096504MUA
A1020B-CQ84B	5962-9096503MTC	5962-9096503MTA
A1020B-1CQ84B	5962-9096504MTC	5962-9096504MTA
A1240A-PG132B	5962-9322101MXC	5962-9322101MXA
A1240A-1PG132B	5962-9322102MXC	5962-9322102MXA
A1280A-PG176B	5962-9215601MXC	5962-9215601MXA
A1280A-1PG176B	5962-9215602MXC	5962-9215602MXA
A1280A-CQ172B	5962-9215601MYC	5962-9215601MYA
A1280A-1CQ172B	5962-9215602MYC	5962-9215602MYA
A1425A-PG133B	5962-9552001MXC	N/A
A1425A-1PG133B	5962-9552002MXC	N/A
A1425A-CQ132B	5962-9552001MYC	N/A
A1425A-1CQ132B	5962-9552002MYC	N/A
A1460A-PG207B	5962-9550801MXC	N/A
A1460A-1PG207B	5962-9550802MXC	N/A
A1460A-CQ196B	5962-9550801MYC	N/A
A1460A-1CQ196B	5962-9550802MYC	N/A
A14100A-PG257B	5962-9552101MXC	N/A
A14100A-1PG257B	5962-9552102MXC	N/A
A14100A-CQ256B	5962-9552101MYC	N/A
A14100A-1CQ256B	5962-9552102MYC	N/A
A32100DX-CQ84B	5962-9875901QXC	N/A
A32100DX-1CQ84B	5962-9857902QXC	N/A
A32200DX-CQ256B	5962-9952701QXC	N/A
A32200DX-1CQ256B	5962-9952702QXC	N/A
A32200DX-CQ208B	5962-9952701QYC	N/A
A32200DX-1CQ208B	5962-9952702QYC	N/A

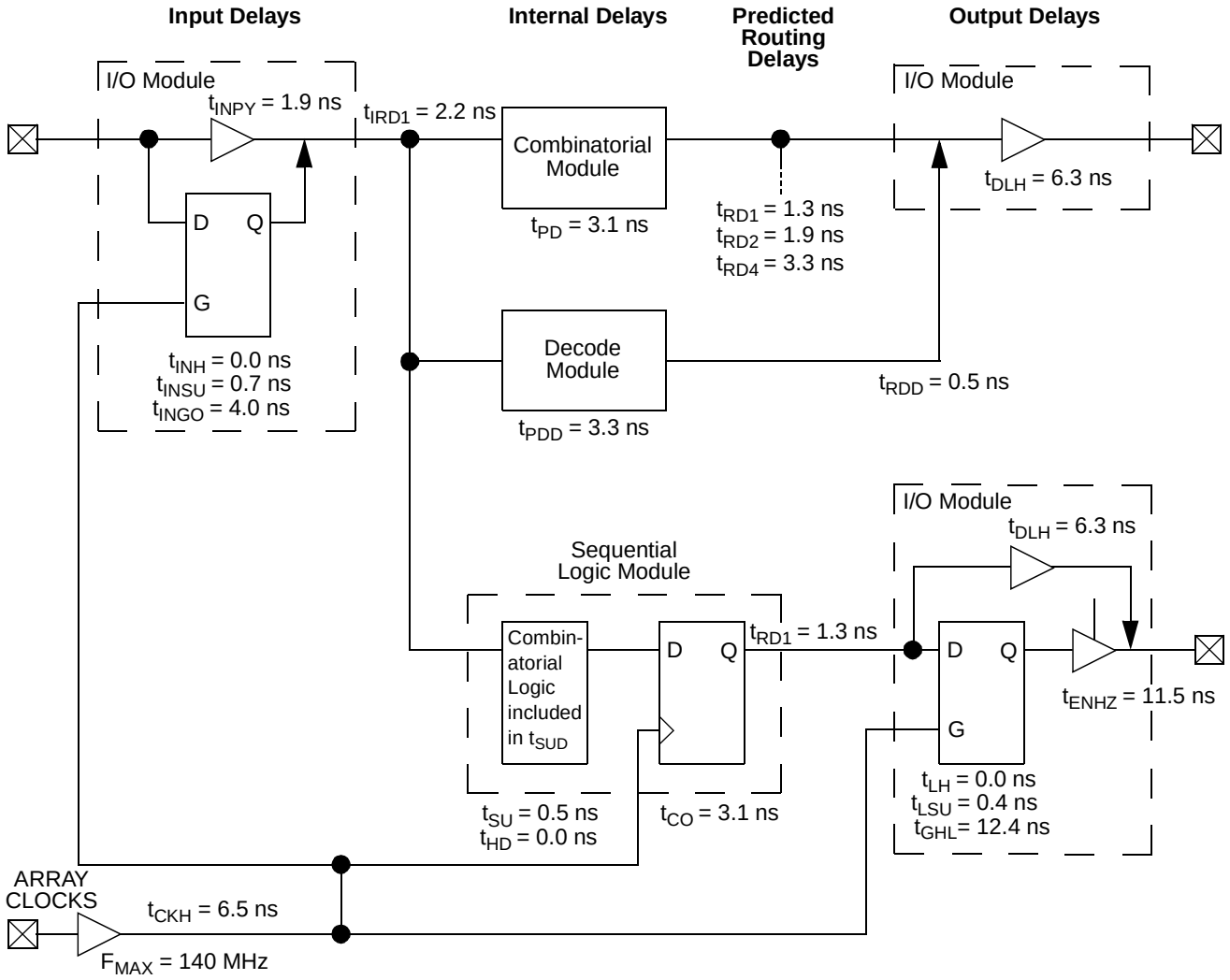
Actel Extended Flow[1]

Step	Screen	Method	Require-ment
1.	Wafer Lot Acceptance[2]	5007 with Step Coverage Waiver	All Lots
2.	Destructive In-Line Bond Pull[3]	2011, Condition D	Sample
3.	Internal Visual	2010, Condition A	100%
4.	Serialization		100%
5.	Temperature Cycling	1010, Condition C	100%
6.	Constant Acceleration	2001, Condition D or E, Y_1 Orientation Only	100%
7.	Particle Impact Noise Detection	2020, Condition A	100%
8.	Radiographic	2012 (one view only)	100%
9.	Pre-Burn-In Test	In accordance with applicable Actel device specification	100%
10.	Burn-in Test	1015, Condition D, 240 hours @ 125°C minimum	100%
11.	Interim (Post-Burn-In) Electrical Parameters	In accordance with applicable Actel device specification	100%
12.	Reverse Bias Burn-In	1015, Condition C, 72 hours @ 150°C minimum	100%
13.	Interim (Post-Burn-In) Electrical Parameters	In accordance with applicable Actel device specification	100%
14.	Percent Defective Allowable (PDA) Calculation	5%, 3% Functional Parameters @ 25°C	All Lots
15.	Final Electrical Test	In accordance with Actel applicable device specification which includes a, b, and c:	100%
	a. Static Tests		100%
	(1) 25°C (Subgroup 1, Table1)	5005	
	(2) –55°C and +125°C (Subgroups 2, 3, Table 1)	5005	
	b. Functional Tests		100%
	(1) 25°C (Subgroup 7, Table 15)	5005	
	(2) –55°C and +125°C (Subgroups 8A and B, Table 1)	5005	
	c. Switching Tests at 25°C (Subgroup 9, Table 1)	5005	100%
16.	Seal	1014	100%
	a. Fine		
	b. Gross		
17.	External Visual	2009	100%

Notes:

1. *Actel offers the extended flow for customers who require additional screening beyond the requirements of the MIL-STD-833, Class B. Actel is compliant to the requirements of MIL-STD-883, Paragraph 1.2.1, and MIL-I-38535, Appendix A. Actel is offering this extended flow incorporating the majority of the screening procedures as outlined in Method 5004 of MIL-STD-883, Class S. The exceptions to Method 5004 are shown in notes 2 and 3 below.*
2. *Wafer lot acceptance is performed to Method 5007; however, the step coverage requirement as specified in Method 2018 must be waived.*
3. *MIL-STD-883, Method 5004 requires 100 percent Radiation latch-up testing (Method 1020). Actel will not be performing any radiation testing, and this requirement must be waived in its entirety.*

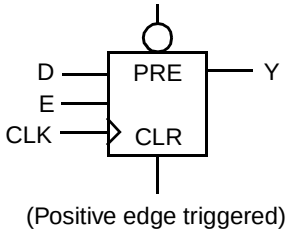
3200DX Timing Model (Logic Functions using Array Clocks)*



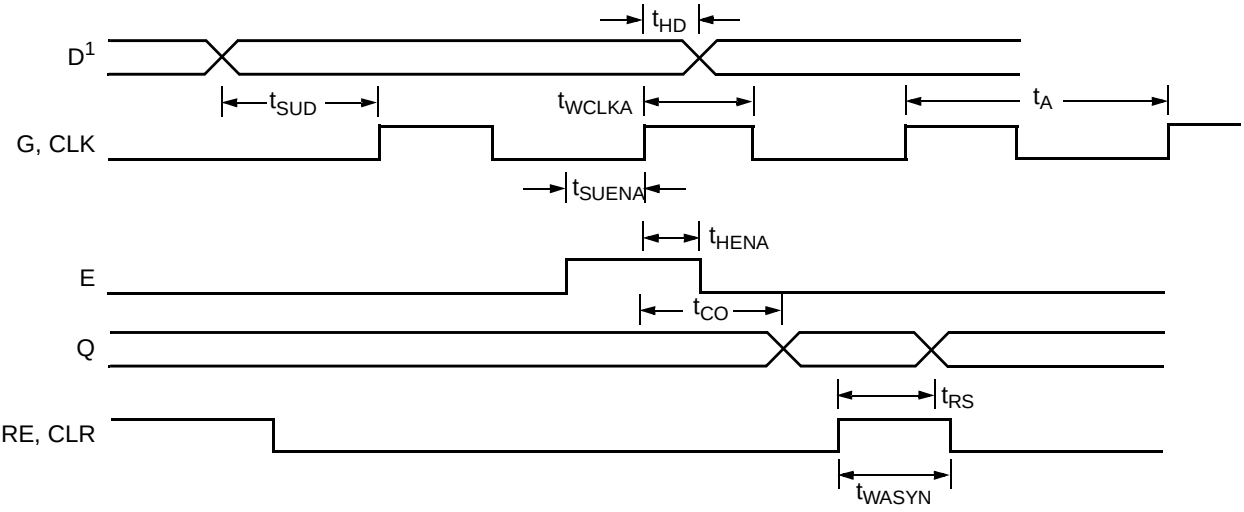
**Values shown for A32100DX–1 at worst-case military conditions.*

Sequential Timing Characteristics (continued)

Flip-Flops and Latches (1200XL/3200DX, ACT 2, and ACT 1)



(Positive edge triggered)



Note:

1. *D represents all data functions involving A, B, and S for multiplexed flip-flops.*

A1240A Timing Characteristics (continued)

(Worst-Case Military Conditions, V_{CC} = 4.5V, T_J = 125°C)

			'–1' Speed		'Std' Speed		
Parameter	**Description**		**Min.**	**Max.**	**Min.**	**Max.**	**Units**
Input Module Propagation Delays							
t_{INYH}	Pad to Y High			4.0		4.7	ns
t_{INYL}	Pad to Y Low			3.6		4.3	ns
t_{INGH}	G to Y High			6.9		8.1	ns
t_{INGL}	G to Y Low			6.6		7.7	ns
Input Module Predicted Routing Delays[1]							
t_{IRD1}	FO=1 Routing Delay			5.8		6.9	ns
t_{IRD2}	FO=2 Routing Delay			6.7		7.8	ns
t_{IRD3}	FO=3 Routing Delay			7.5		8.8	ns
t_{IRD4}	FO=4 Routing Delay			8.2		9.7	ns
t_{IRD8}	FO=8 Routing Delay			10.9		12.9	ns
Global Clock Network							
t_{CKH}	Input Low to High	FO = 32 FO = 256		13.3 16.3		15.7 19.2	ns
t_{CKL}	Input High to Low	FO = 32 FO = 256		13.3 16.5		15.7 19.5	ns
t_{PWH}	Minimum Pulse Width High	FO = 32 FO = 256	5.7 6.0		6.7 7.1		ns
t_{PWL}	Minimum Pulse Width Low	FO = 32 FO = 256	5.7 6.0		6.7 7.1		ns
t_{CKSW}	Maximum Skew	FO = 32 FO = 256		0.6 3.1		0.6 3.1	ns
t_{SUEXT}	Input Latch External Setup	FO = 32 FO = 256	0.0 0.0		0.0 0.0		ns
t_{HEXT}	Input Latch External Hold	FO = 32 FO = 256	8.6 13.8		8.6 13.8		ns
t_P	Minimum Period	FO = 32 FO = 256	11.5 12.2		13.5 14.3		ns
f_{MAX}	Maximum Frequency	FO = 32 FO = 256		87 82		74 70	MHz

Note:

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment. Optimization techniques may further reduce delays by 0 to 4 ns.

A1460A Timing Characteristics

(Worst-Case Military Conditions, V_{CC} = 4.5V, T_J = 125°C)

		'–1' Speed		'Std' Speed		
Parameter	**Description**	**Min.**	**Max.**	**Min.**	**Max.**	**Units**
Logic Module Propagation Delays[1]						
t_{PD}	Internal Array Module		3.0		3.5	ns
t_{CO}	Sequential Clock to Q		3.0		3.5	ns
t_{CLR}	Asynchronous Clear to Q		3.0		3.5	ns
Logic Module Predicted Routing Delays[2]						
t_{RD1}	FO=1 Routing Delay		1.3		1.5	ns
t_{RD2}	FO=2 Routing Delay		1.9		2.1	ns
t_{RD3}	FO=3 Routing Delay		2.1		2.5	ns
t_{RD4}	FO=4 Routing Delay		2.6		2.9	ns
t_{RD8}	FO=8 Routing Delay		4.2		4.9	ns
Logic Module Sequential Timing						
t_{SUD}	Flip-Flop (Latch) Data Input Setup	0.9		1.0		ns
t_{HD}	Flip-Flop (Latch) Data Input Hold	0.0		0.0		ns
t_{SUENA}	Flip-Flop (Latch) Enable Setup	0.9		1.0		ns
t_{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		ns
t_{WASYN}	Asynchronous Pulse Width	4.8		5.6		ns
t_{WCLKA}	Flip-Flop Clock Pulse Width	4.8		5.6		ns
t_{A}	Flip-Flop Clock Input Period	9.9		11.6		ns
f_{MAX}	Flip-Flop Clock Frequency		100		85	MHz
Input Module Propagation Delays						
t_{INY}	Input Data Pad to Y		4.2		4.9	ns
t_{ICKY}	Input Reg IOCLK Pad to Y		7.0		8.2	ns
t_{OCKY}	Output Reg IOCLK Pad to Y		7.0		8.2	ns
t_{ICLRY}	Input Asynchronous Clear to Y		7.0		8.2	ns
t_{OCLRY}	Output Asynchronous Clear to Y		7.0		8.2	ns
Input Module Predicted Routing Delays[2, 3]						
t_{IRD1}	FO=1 Routing Delay		1.3		1.5	ns
t_{IRD2}	FO=2 Routing Delay		1.9		2.1	ns
t_{IRD3}	FO=3 Routing Delay		2.1		2.5	ns
t_{IRD4}	FO=4 Routing Delay		2.6		2.9	ns
t_{IRD8}	FO=8 Routing Delay		4.2		4.9	ns

Notes:

1. *For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{CO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.*
2. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.*
3. *Optimization techniques may further reduce delays by 0 to 4 ns.*

A1460A Timing Characteristics (continued)

(Worst-Case Military Conditions, V_{CC} = 4.5V, T_J = 125°C)

		'–1' Speed		'Std' Speed		
Parameter	**Description**	**Min.**	**Max.**	**Min.**	**Max.**	**Units**
I/O Module Sequential Timing						
t_{INH}	Input F-F Data Hold (w.r.t. IOCLK Pad)	0.0		0.0		ns
t_{INSU}	Input F-F Data Setup (w.r.t. IOCLK Pad)	2.1		2.4		ns
t_{IDEH}	Input Data Enable Hold (w.r.t. IOCLK Pad)	0.0		0.0		ns
t_{IDESU}	Input Data Enable Setup (w.r.t. IOCLK Pad)	8.7		10.0		ns
t_{OUTH}	Output F-F Data Hold (w.r.t. IOCLK Pad)	1.1		1.2		ns
t_{OUTSU}	Output F-F Data Setup (w.r.t. IOCLK Pad)	1.1		1.2		ns
t_{ODEH}	Output Data Enable Hold (w.r.t. IOCLK Pad)	0.5		0.6		ns
t_{ODESU}	Output Data Enable Setup (w.r.t. IOCLK Pad)	2.0		2.4		ns
TTL Output Module Timing[1]						
t_{DHS}	Data to Pad, High Slew		7.5		8.9	ns
t_{DLS}	Data to Pad, Low Slew		11.9		14.0	ns
t_{ENZHS}	Enable to Pad, Z to H/L, High Slew		6.0		7.0	ns
t_{ENZLS}	Enable to Pad, Z to H/L, Low Slew		10.9		12.8	ns
t_{ENHSZ}	Enable to Pad, H/L to Z, High Slew		11.5		13.5	ns
t_{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		10.9		12.8	ns
t_{CKHS}	IOCLK Pad to Pad H/L, High Slew		11.6		13.4	ns
t_{CKLS}	IOCLK Pad to Pad H/L, Low Slew		17.8		19.8	ns
d_{TLHHS}	Delta Low to High, High Slew		0.04		0.04	ns/pF
d_{TLHLS}	Delta Low to High, Low Slew		0.07		0.08	ns/pF
d_{THLHS}	Delta High to Low, High Slew		0.05		0.06	ns/pF
d_{THLLS}	Delta High to Low, Low Slew		0.07		0.08	ns/pF

Note:

1. Delays based on 35 pF loading.

A14100A Timing Characteristics (continued)

(Worst-Case Military Conditions, V_{CC} = 4.5V, T_J = 125°C)

		'–1' Speed		'Std' Speed		
Parameter	**Description**	**Min.**	**Max.**	**Min.**	**Max.**	**Units**
Routed Array Clock Networks						
t_{RCKH}	Input Low to High (FO=256)		9.0		10.5	ns
t_{RCKL}	Input High to Low (FO=256)		9.0		10.5	ns
t_{RPWH}	Min. Pulse Width High (FO=256)	6.3		7.1		ns
t_{RPWL}	Min. Pulse Width Low (FO=256)	6.3		7.1		ns
t_{RCKSW}	Maximum Skew (FO=128)		1.9		2.1	ns
t_{RP}	Minimum Period (FO=256)	12.9		14.5		ns
f_{RMAX}	Maximum Frequency (FO=256)		75		65	MHz
Clock-to-Clock Skews						
$t_{IOHCKSW}$	I/O Clock to H-Clock Skew	0.0	3.5	0.0	3.5	ns
$t_{IORCKSW}$	I/O Clock to R-Clock Skew	0.0	5.0	0.0	5.0	ns
t_{HRCKSW}	H-Clock to R-Clock Skew (FO = 64) (FO = 50% max.)	 0.0 0.0	 1.0 3.0	 0.0 0.0	 1.0 3.0	ns

A32100DX Timing Characteristics (continued)

(Worst-Case Military Conditions, V_{CC} = 4.5V, T_J = 125°C)

		'–1' Speed		'Std' Speed		
Parameter	**Description**	**Min.**	**Max.**	**Min.**	**Max.**	**Units**
TTL Output Module Timing[1]						
t_{DLH}	Data to Pad High		5.1		6.8	ns
t_{DHL}	Data to Pad Low		6.3		8.3	ns
t_{ENZH}	Enable Pad Z to High		6.6		8.8	ns
t_{ENZL}	Enable Pad Z to Low		7.1		9.4	ns
t_{ENHZ}	Enable Pad High to Z		11.5		15.3	ns
t_{ENLZ}	Enable Pad Low to Z		11.5		15.3	ns
t_{GLH}	G to Pad High		11.5		15.3	ns
t_{GHL}	G to Pad Low		12.4		16.6	ns
t_{LSU}	I/O Latch Output Setup	0.4		0.5		ns
t_{LH}	I/O Latch Output Hold	0.0		0.0		ns
t_{LCO}	I/O Latch Clock-Out (Pad-to-Pad) 32 I/O		11.5		15.4	ns
t_{ACO}	Array Latch Clock-Out (Pad-to-Pad) 32 I/O		16.3		21.7	ns
d_{TLH}	Capacitive Loading, Low to High		0.04		0.06	ns/pF
d_{THL}	Capacitive Loading, High to Low		0.06		0.08	ns/pF
t_{WDO}	Hard-Wired Wide Decode Output		0.05		0.07	ns
CMOS Output Module Timing[1]						
t_{DLH}	Data to Pad High		6.3		8.3	ns
t_{DHL}	Data to Pad Low		5.1		6.8	ns
t_{ENZH}	Enable Pad Z to High		6.6		8.8	ns
t_{ENZL}	Enable Pad Z to Low		7.1		9.4	ns
t_{ENHZ}	Enable Pad High to Z		11.5		15.3	ns
t_{ENLZ}	Enable Pad Low to Z		11.5		15.3	ns
t_{GLH}	G to Pad High		11.5		15.3	ns
t_{GHL}	G to Pad Low		12.4		16.6	ns
t_{LSU}	I/O Latch Setup	0.4		0.5		ns
t_{LH}	I/O Latch Hold	0.0		0.0		ns
t_{LCO}	I/O Latch Clock-Out (Pad-to-Pad) 32 I/O		13.7		18.2	ns
t_{ACO}	Array Latch Clock-Out (Pad-to-Pad) 32 I/O		19.2		25.6	ns
d_{TLH}	Capacitive Loading, Low to High		0.06		0.08	ns/pF
d_{THL}	Capacitive Loading, High to Low		0.05		0.07	ns/pF
t_{WDO}	Hard-Wired Wide Decode Output		0.05		0.07	ns

Notes:

1. *Delays based on 35 pF loading.*
2. *SSO information can be found in the* Simultaneously Switching Output Limits for Actel FPGAs *application note at http://www.actel.com/appnotes.*

A32200DX Timing Characteristics

(Worst-Case Military Conditions, V_{CC} = 4.5V, T_J = 125°C)

		'–1' Speed		'Std' Speed		
Parameter	**Description**	**Min.**	**Max.**	**Min.**	**Max.**	**Units**
Logic Module Combinatorial Functions						
t_{PD}	Internal Array Module Delay		2.8		3.8	ns
t_{PDD}	Internal Decode Module Delay		3.4		4.6	ns
Logic Module Predicted Routing Delays[1]						
t_{RD1}	FO=1 Routing Delay		1.6		2.1	ns
t_{RD2}	FO=2 Routing Delay		2.3		3.1	ns
t_{RD3}	FO=3 Routing Delay		2.9		3.9	ns
t_{RD4}	FO=4 Routing Delay		3.5		4.7	ns
t_{RD5}	FO=8 Routing Delay		6.2		8.2	ns
t_{RDD}	Decode-to-Output Routing Delay		0.8		1.1	ns
Logic Module Sequential Timing Characteristics						
t_{CO}	Flip-Flop Clock-to-Output		3.2		4.2	ns
t_{GO}	Latch Gate-to-Output		2.8		3.8	ns
t_{SU}	Flip-Flop (Latch) Setup Time	0.5		0.6		ns
t_{H}	Flip-Flop (Latch) Hold Time	0.0		0.0		ns
t_{RO}	Flip-Flop (Latch) Reset to Output		3.2		4.2	ns
t_{SUENA}	Flip-Flop (Latch) Enable Setup	0.9		1.2		ns
t_{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		ns
t_{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	4.3		5.8		ns
t_{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	5.7		7.6		ns

Note:

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

Pin Description

CLK Clock (Input)

ACT 1 only. TTL Clock input for global clock distribution network. The Clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

CLKA Clock A (Input)

ACT 2, 1200XL, 3200DX, and ACT 3 only. TTL Clock input for global clock distribution networks. The Clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

CLKB Clock B (Input)

ACT 2, 1200XL, 3200DX, and ACT 3 only. TTL Clock input for global clock distribution networks. The Clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

DCLK Diagnostic Clock (Input)

TTL Clock input for diagnostic probe and device programming. DCLK is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

GND Ground

LOW supply voltage.

HCLK Dedicated (Hard-wired) Array Clock (Input)

ACT 3 only. TTL Clock input for sequential modules. This input is directly wired to each S-module and offers clock speeds independent of the number of S-modules being driven. This pin can also be used as an I/O.

I/O Input/Output (Input, Output)

I/O pin functions as an input, output, tristate, or bi-directional buffer. Input and output levels are compatible with standard TTL and CMOS specifications. In the ACT 3 and 3200DX families, unused I/Os are automatically tri-stated. With this configuration, the input buffer internal to the I/O module is disabled. In the ACT 1, ACT 2 and 1200XL families, unused I/Os are automatically configured as bi-directional buffers where each buffer is configured as a LOW driver.

IOCLK Dedicated (Hard-wired) I/O Clock (Input)

ACT 3 only. TTL Clock input for I/O modules. This input is directly wired to each I/O module and offers clock speeds independent of the number of I/O modules being driven. This pin can also be used as an I/O.

IOPCL Dedicated (Hard-wired) I/O Preset/Clear (Input)

ACT 3 only. TTL input for I/O preset or clear. This global input is directly wired to the preset and clear inputs of all I/O registers. This pin functions as an I/O when no I/O preset or clear macros are used.

MODE Mode (Input)

The MODE pin controls the use of diagnostic pins (DCLK, PRA, PRB, SDI). When the MODE pin is HIGH, the special functions are active. When the MODE pin is LOW, the pins function as I/Os. To provide debugging capability, the MODE pin should be terminated to GND through a 10 kΩ resistor so that the MODE pin can be pulled high when required.

NC No Connection

This pin is not connected to circuitry within the device.

PRA, I/O Probe A (Output)

The Probe A pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the Probe B pin to allow real-time diagnostic output of any signal path within the device. The Probe A pin can be used as a user-defined I/O when debugging has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality. PRA is accessible when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

PRB, I/O Probe B (Output)

The Probe B pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the Probe A pin to allow real-time diagnostic output of any signal path within the device. The Probe B pin can be used as a user-defined I/O when verification has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality. PRB is accessible when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

SDI Serial Data Input (Input)

Serial data input for diagnostic probe and device programming. SDI is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

V_{CC} 5.0V Supply Voltage

HIGH supply voltage.

QCLKA/B,C,D Quadrant Clock (Input/Output)

3200DX only. These four pins are the quadrant clock inputs. When not used as a register control signal, these pins can function as general purpose I/O.

TCK Test Clock

Clock signal to shift the JTAG data into the device. This pin functions as an I/O when the JTAG fuse is not programmed. JTAG pins are only available in the 3200DX device.

TDI Test Data In

Serial data input for JTAG instructions and data. Data is shifted in on the rising edge of TCLK. This pin functions as an I/O when the JTAG fuse is not programmed. JTAG pins are only available in the 3200DX device.

TDO Test Data Out

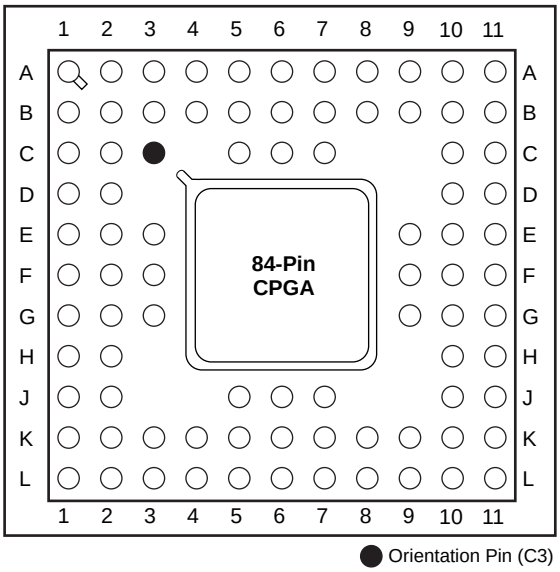
Serial data output for JTAG instructions and test data. This pin functions as an I/O when the JTAG fuse is not programmed. JTAG pins are only available in the 3200DX device.

TMS Test Mode Select

Serial data input for JTAG test mode. Data is shifted in on the rising edge of TCLK. This pin functions as an I/O when the JTAG fuse is not programmed. JTAG pins are only available in the 3200DX device.

Package Pin Assignments

84-Pin CPGA (Top View)



176-Pin CPGA (Continued)

Pin Number	A1280A Function	A1280XL Function
H12	GND	GND
H13	V_{CC}	V_{CC}
H14	V_{CC}	V_{CC}
H15	I/O	I/O
J1	I/O	I/O
J2	I/O	I/O
J3	I/O	I/O
J4	V_{CC}	V_{CC}
J12	GND	GND
J13	GND	GND
J14	V_{CC}	V_{CC}
J15	I/O	I/O
K1	I/O	I/O
K2	I/O	I/O
K3	I/O	I/O
K4	GND	GND
K12	GND	GND
K13	I/O	I/O
K14	I/O	I/O
K15	I/O	I/O
L1	I/O	I/O
L2	I/O	I/O
L3	I/O	I/O
L4	GND	GND
L12	I/O	I/O
L13	I/O	I/O
L14	I/O	I/O
L15	I/O	I/O
M1	I/O	I/O
M2	I/O	I/O
M3	I/O	I/O
M4	GND	GND
M5	V_{CC}	V_{CC}
M6	GND	GND
M7	I/O	I/O
M8	GND	GND
M9	I/O	I/O
M10	GND	GND
M11	V_{CC}	V_{CC}
M12	GND	GND
M13	I/O	I/O
M14	I/O	I/O
M15	I/O	I/O
N1	I/O	I/O

Pin Number	A1280A Function	A1280XL Function
N2	I/O	I/O
N3	I/O	I/O
N4	I/O	I/O
N5	I/O	I/O
N6	I/O	I/O
N7	I/O	I/O
N8	V_{CC}	V_{CC}
N9	I/O	I/O
N10	I/O	I/O
N11	I/O	I/O
N12	I/O	I/O
N13	I/O	I/O
N14	I/O	I/O
N15	I/O	I/O
P1	I/O	I/O
P2	I/O	I/O
P3	I/O	I/O
P4	I/O	I/O
P5	I/O	I/O
P6	I/O	I/O
P7	I/O	I/O
P8	I/O	I/O
P9	I/O	I/O
P10	I/O	I/O
P11	I/O	I/O
P12	I/O	I/O
P13	I/O	I/O
P14	I/O	I/O
P15	I/O	I/O
R1	I/O	I/O
R2	I/O	I/O
R3	I/O	I/O
R4	I/O	I/O
R5	I/O	I/O
R6	I/O	I/O
R7	I/O	I/O
R8	I/O	I/O
R9	I/O	I/O
R10	I/O	I/O
R11	I/O	I/O
R12	I/O	I/O
R13	I/O	I/O
R14	I/O	I/O
R15	I/O	I/O

207-Pin CPGA

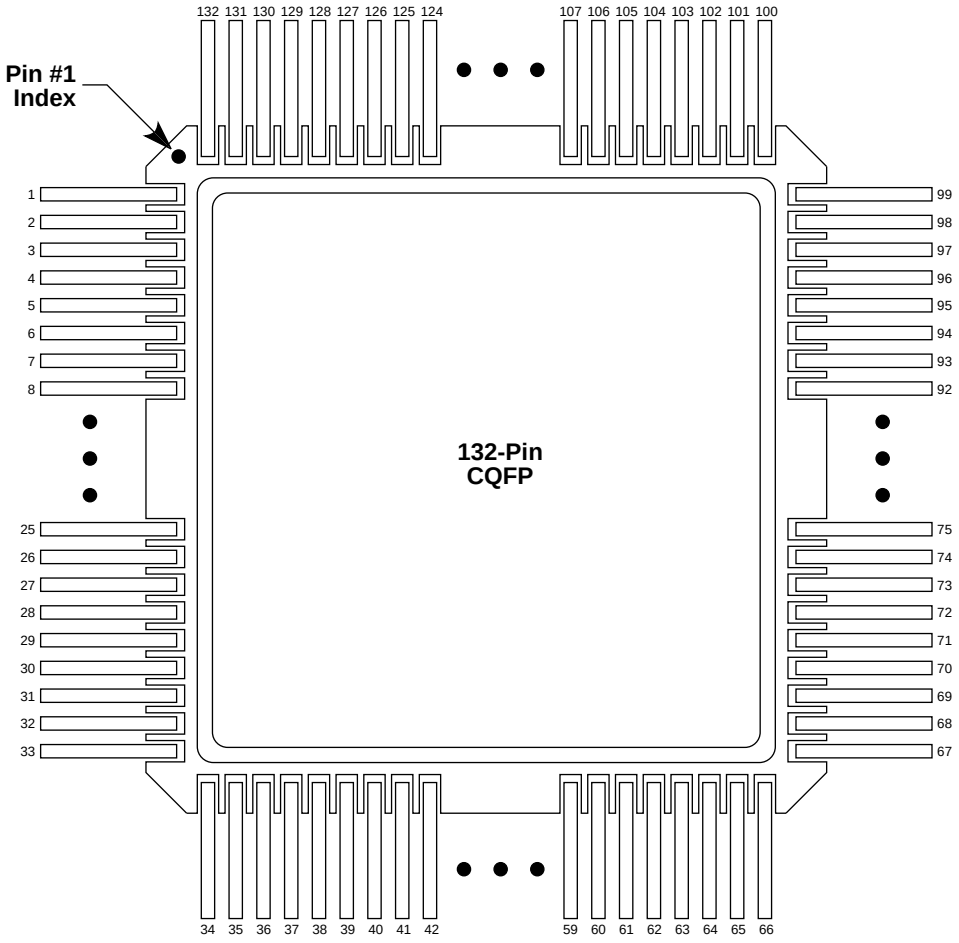
Pin Number	A1460A Function
A1	NC
A2	NC
A3	I/O
A4	I/O
A5	I/O
A6	I/O
A7	I/O
A8	I/O
A9	I/O
A10	I/O
A11	I/O
A12	I/O
A13	I/O
A14	I/O
A15	I/O
A16	NC
A17	NC
B1	NC
B2	V_{CC}
B3	I/O
B4	I/O
B5	I/O
B6	I/O
B7	I/O
B8	I/O
B9	V_{CC}
B10	I/O
B11	I/O
B12	I/O
B13	I/O
B14	I/O
B15	I/O
B16	V_{CC}
B17	NC
C1	NC
C2	NC
C3	SDI, I/O
C4	I/O
C5	I/O
C6	I/O
C7	I/O
C8	I/O
C9	I/O

Pin Number	A1460A Function
C10	I/O
C11	I/O
C12	I/O
C13	I/O
C14	I/O
C15	GND
C16	I/O
C17	I/O
D1	I/O
D2	I/O
D3	I/O
D4	GND
D5	GND
D6	I/O
D7	MODE
D8	I/O
D9	GND
D10	I/O
D11	V_{CC}
D12	I/O
D13	I/O
D14	GND
D15	I/O
D16	I/O
D17	I/O
E1	I/O
E2	I/O
E3	I/O
E4	DCLK, I/O
E14	I/O
E15	I/O
E16	I/O
E17	I/O
F1	I/O
F2	I/O
F3	I/O
F4	I/O
F14	I/O
F15	I/O
F16	I/O
F17	I/O
G1	I/O
G2	I/O

Pin Number	A1460A Function
G3	I/O
G4	I/O
G14	I/O
G15	I/O
G16	I/O
G17	I/O
H1	PRA, I/O
H2	I/O
H3	I/O
H4	I/O
H14	I/O
H15	I/O
H16	I/O
H17	I/O
J1	I/O
J2	V_{CC}
J3	CLKB, I/O
J4	GND
J14	GND
J15	HCLK, I/O
J16	V_{CC}
J17	I/O
K1	CLKA, I/O
K2	I/O
K3	I/O
K4	I/O
K14	I/O
K15	I/O
K16	PRB, I/O
K17	I/O
L1	I/O
L2	I/O
L3	I/O
L4	I/O
L14	I/O
L15	I/O
L16	I/O
L17	I/O
M1	I/O
M2	I/O
M3	I/O
M4	I/O
M14	I/O

Package Pin Assignments (continued)

132-Pin CQFP (Top View)



132-Pin CQFP

Pin Number	A1425A Function
1	NC
2	GND
3	SDI, I/O
4	I/O
5	I/O
6	I/O
7	I/O
8	I/O
9	MODE
10	GND
11	V_{CC}
12	I/O
13	I/O
14	I/O
15	I/O
16	I/O
17	I/O
18	I/O
19	I/O
20	I/O
21	I/O
22	V_{CC}
23	I/O
24	I/O
25	I/O
26	GND
27	V_{CC}
28	I/O
29	I/O
30	I/O
31	I/O
32	I/O
33	I/O
34	NC
35	I/O
36	GND
37	I/O
38	I/O
39	I/O
40	I/O
41	I/O
42	GND
43	V_{CC}
44	I/O

Pin Number	A1425A Function
45	I/O
46	I/O
47	I/O
48	PRB, I/O
49	I/O
50	HCLK, I/O
51	I/O
52	I/O
53	I/O
54	I/O
55	I/O
56	I/O
57	I/O
58	GND
59	V_{CC}
60	I/O
61	I/O
62	I/O
63	I/O
64	IOPCL, I/O
65	GND
66	NC
67	NC
68	I/O
69	I/O
70	I/O
71	I/O
72	I/O
73	I/O
74	GND
75	V_{CC}
76	I/O
77	I/O
78	V_{CC}
79	I/O
80	I/O
81	I/O
82	I/O
83	I/O
84	I/O
85	I/O
86	I/O
87	I/O
88	I/O

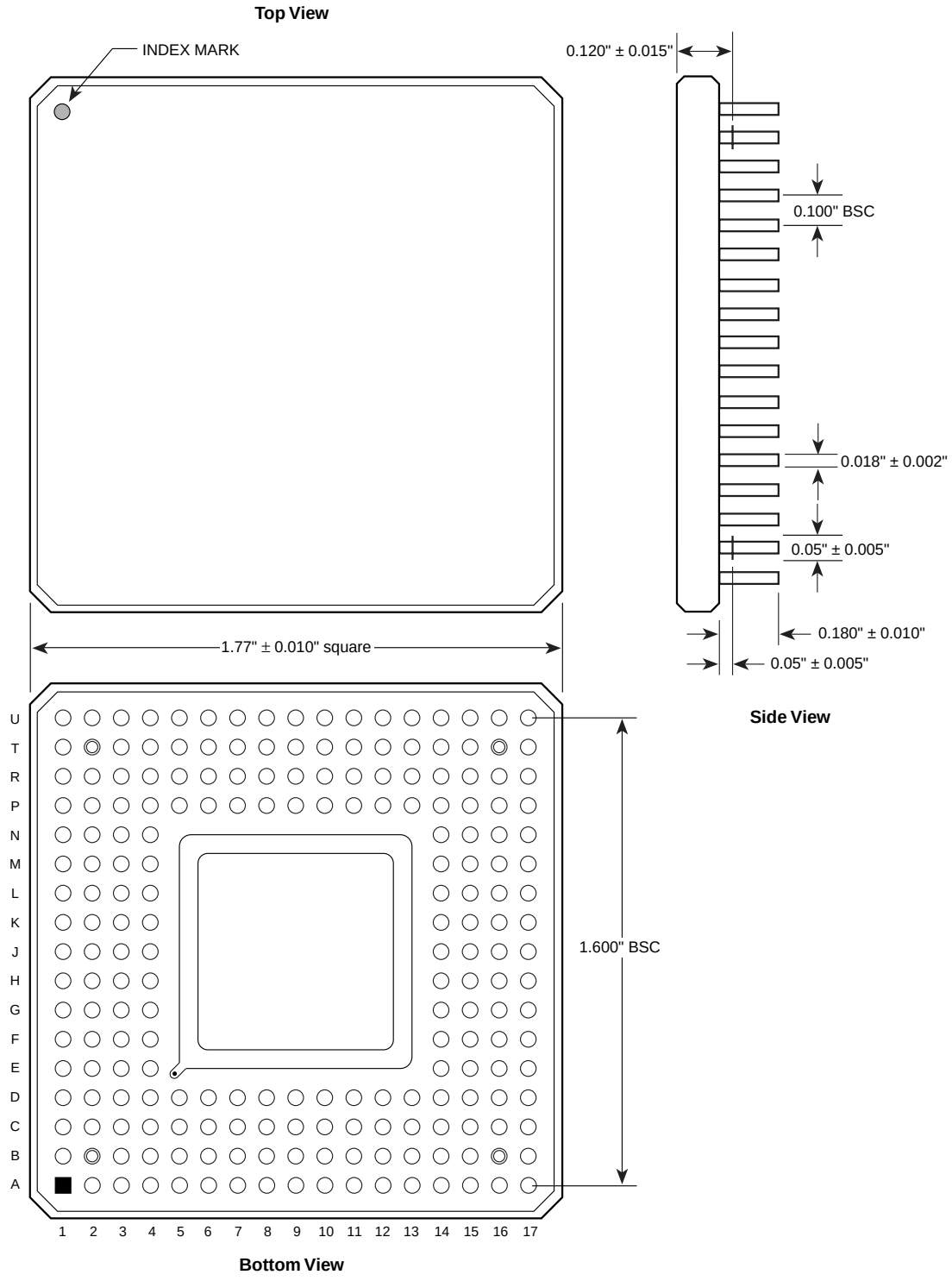
Pin Number	A1425A Function
89	V_{CC}
90	GND
91	V_{CC}
92	GND
93	I/O
94	I/O
95	I/O
96	I/O
97	I/O
98	IOCLK, I/O
99	NC
100	NC
101	GND
102	I/O
103	I/O
104	I/O
105	I/O
106	GND
107	V_{CC}
108	I/O
109	I/O
110	I/O
111	I/O
112	I/O
113	I/O
114	I/O
115	I/O
116	CLKA, I/O
117	CLKB, I/O
118	PRA, I/O
119	I/O
120	I/O
121	I/O
122	GND
123	V_{CC}
124	I/O
125	I/O
126	I/O
127	I/O
128	I/O
129	I/O
130	I/O
131	DCLK, I/O
132	NC

256-Pin CQFP

Pin Number	A14100A Function	A32200DX Function
1	GND	NC
2	SDI, I/O	GND
3	I/O	I/O
4	I/O	I/O
5	I/O	I/O
6	I/O	I/O
7	I/O	I/O
8	I/O	I/O
9	I/O	I/O
10	I/O	GND
11	MODE	I/O
12	I/O	I/O
13	I/O	I/O
14	I/O	I/O
15	I/O	I/O
16	I/O	I/O
17	I/O	I/O
18	I/O	I/O
19	I/O	I/O
20	I/O	I/O
21	I/O	I/O
22	I/O	I/O
23	I/O	I/O
24	I/O	I/O
25	I/O	I/O
26	I/O	V_{CC}
27	I/O	I/O
28	V_{CC}	I/O
29	GND	V_{CC}
30	V_{CC}	V_{CC}
31	GND	GND
32	I/O	V_{CC}
33	I/O	GND
34	I/O	TCK, I/O
35	I/O	I/O
36	I/O	GND
37	I/O	I/O
38	I/O	I/O
39	I/O	I/O
40	I/O	I/O
41	I/O	I/O
42	I/O	I/O
43	I/O	I/O
44	I/O	I/O
45	I/O	I/O
46	V_{CC}	I/O
47	I/O	I/O
48	I/O	GND
49	I/O	I/O
50	I/O	I/O
51	I/O	I/O
52	I/O	I/O
53	I/O	I/O
54	I/O	I/O
55	I/O	I/O
56	I/O	I/O
57	I/O	I/O
58	I/O	I/O
59	GND	I/O
60	I/O	V_{CC}
61	I/O	GND
62	I/O	GND
63	I/O	NC
64	I/O	NC
65	I/O	NC
66	I/O	I/O
67	I/O	SDO, I/O
68	I/O	I/O
69	I/O	I/O (WD)
70	I/O	I/O (WD)
71	I/O	I/O
72	I/O	V_{CC}
73	I/O	I/O
74	I/O	I/O
75	I/O	I/O
76	I/O	I/O (WD)
77	I/O	GND
78	I/O	I/O (WD)
79	I/O	I/O
80	I/O	QCLKB, I/O
81	I/O	I/O
82	I/O	I/O
83	I/O	I/O
84	I/O	I/O
85	I/O	I/O
86	I/O	I/O
87	I/O	I/O (WD)
88	I/O	I/O (WD)
89	I/O	I/O
90	PRB, I/O	I/O
91	GND	I/O
92	V_{CC}	I/O
93	GND	I/O
94	V_{CC}	I/O
95	I/O	V_{CC}
96	HCLK, I/O	V_{CC}
97	I/O	GND
98	I/O	GND
99	I/O	I/O
100	I/O	I/O
101	I/O	I/O
102	I/O	I/O
103	I/O	I/O
104	I/O	I/O
105	I/O	I/O (WD)
106	I/O	I/O (WD)
107	I/O	I/O
108	I/O	I/O
109	I/O	I/O (WD)
110	GND	I/O (WD)
111	I/O	I/O
112	I/O	QCLKA, I/O
113	I/O	I/O
114	I/O	GND
115	I/O	I/O
116	I/O	I/O
117	I/O	I/O
118	I/O	I/O
119	I/O	V_{CC}
120	I/O	I/O
121	I/O	I/O (WD)
122	I/O	I/O (WD)
123	I/O	I/O
124	I/O	I/O
125	I/O	TDI, I/O
126	I/O	TMS, I/O
127	IOPCL, I/O	GND
128	GND	NC
129	I/O	NC
130	I/O	NC
131	I/O	GND
132	I/O	I/O

Package Mechanical Drawings (continued)

207-Pin CPGA

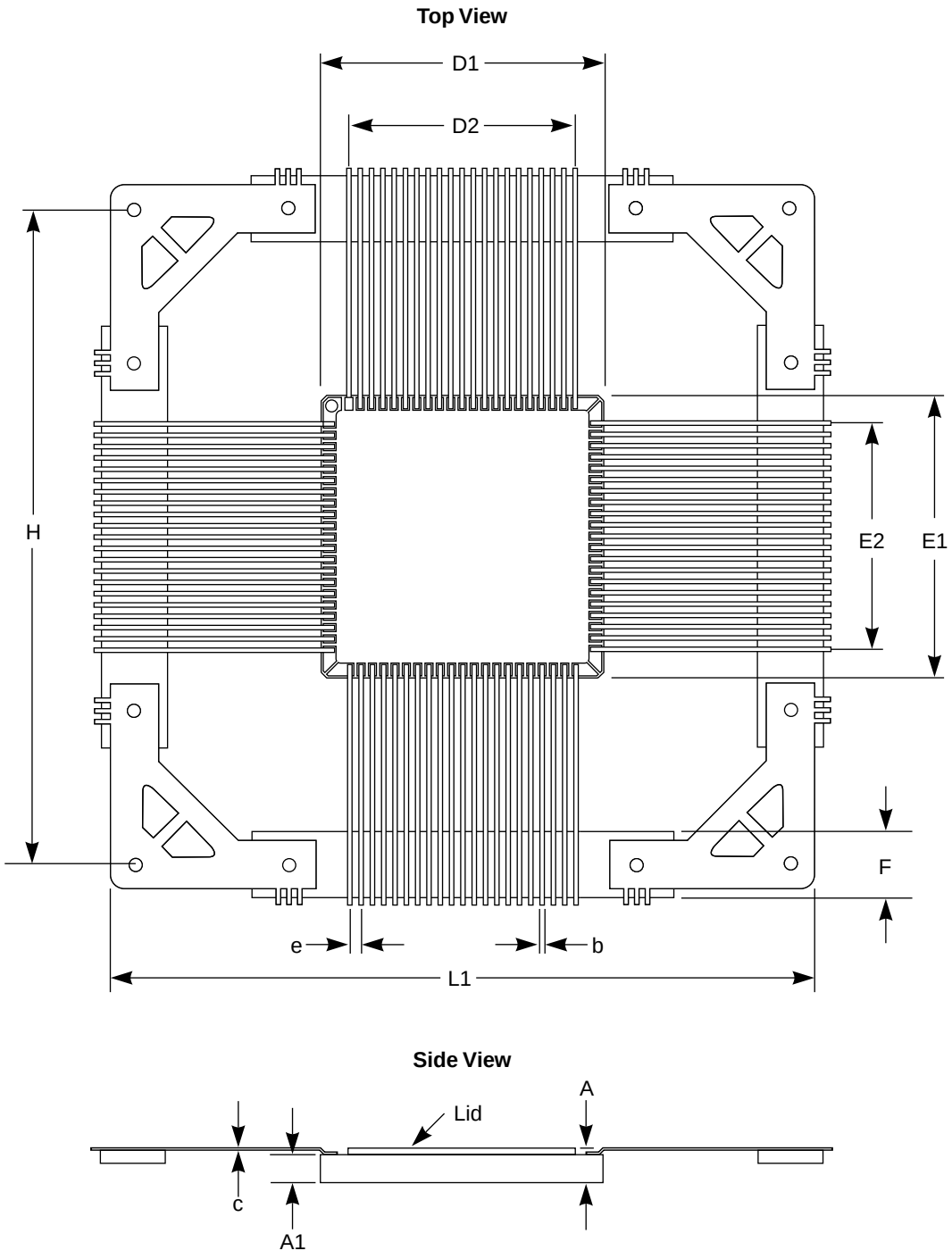


Notes:

1. *All dimensions are in inches unless otherwise stated.*
2. *BSC—Basic Spacing between Centers. This is a theoretical true position dimension and so has no tolerance.*

Package Mechanical Drawings (continued)

84-Pin CQFP



Notes:

1. *Seal ring and lid are connected to Ground.*
2. *Lead material is Kovar with minimum 50 microinches gold plate over nickel.*
3. *Packages are shipped unformed with the ceramic tie bar in a test carrier.*